



## UNITED STATES PATENT AND TRADEMARK OFFICE

COMMISSIONER FOR PATENTS  
UNITED STATES PATENT AND TRADEMARK OFFICE  
WASHINGTON, D.C. 20231  
www.uspto.gov



Bib Data Sheet

CONFIRMATION NO. 8779

BEST AVAILABLE COPY

SERIAL NUMBER	FILING DATE	CLASS	GROUP ART UNIT	ATTORNEY DOCKET NO.
09/891,511	06/27/2001	438	2812	010819
RULE				

## APPLICANTS

Mamoru Nakasuji, Kanagawa, JAPAN;  
Nobuharu Noji, Kanagawa, JAPAN;  
Tohru Satake, Kanagawa, JAPAN;  
Masahiro Hatakeyama, Kanagawa, JAPAN;  
Toshifumi Kimba, Kanagawa, JAPAN;  
Hiroshi Sobukawa, Kanagawa, JAPAN;  
Shoji Yoshikawa, Tokyo, JAPAN;  
Takeshi Murakami, Tokyo, JAPAN;  
Kenji Watanabe, Kanagawa, JAPAN;  
Tsutomu Karimata, Kanagawa, JAPAN;  
Shin Oowada, Kanagawa, JAPAN;  
Mutsumi Saito, Kanagawa, JAPAN;  
Yuichiro Yamazaki, Tokyo, JAPAN;  
Takamitsu Nagai, Kanagawa, JAPAN;  
Ichirota Nagahama, Kanagawa, JAPAN;

\*\* CONTINUING DATA \*\*\*\*\* *none* *gib*

\*\* FOREIGN APPLICATIONS \*\*\*\*\*

JAPAN 2000-193104 06/27/2000  
JAPAN 2000-229101 07/28/2000  
JAPAN 2000-335934 11/02/2000  
JAPAN 2001-11218 01/19/2001  
JAPAN 2001-31901 02/08/2001  
JAPAN 2001-31906 02/08/2001  
JAPAN 2001-33599 02/09/2001  
JAPAN 2001-35089 02/13/2001  
JAPAN 2001-158662 05/28/2001  
JAPAN 2001-162041 05/30/2001  
JAPAN 2001-189304 06/22/2001

BEST AVAILABLE COPY

IF REQUIRED, FOREIGN FILING LICENSE GRANTED

\*\* 08/29/2001

Foreign Priority claimed	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no	STATE OR COUNTRY	SHEETS DRAWING	TOTAL CLAIMS	INDEPENDENT CLAIMS
35 USC 119 (e-d) conditions met	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Not after	JAPAN	50	60	13
Verified and Acknowledged	Advantage <i>gib</i> Examiner's Signature				

ADDRESS

23850

TITLE

Inspection system by charged particle beam and method of manufacturing devices using the system